Structural test generation with employment of multiple observation time strategy

Skobtsov, Vadim BEC'96: the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia: proceedings 1996 / p. 299-302: ill

Test generation for sequential digital systems based on symbolic simulation

Skobtsov, Vadim; Skobtsov, Yu. BEC'98: the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia: proceedings 1998 / p. 341-344: ill